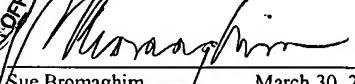


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Sue Bromaghim

March 30, 2006

CUSTOMER NO. 36257

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Ibrahim ABDULHALIM et al.

Title: Periodic Patterns and Technique to Control Misalignment Between Two Layers

Application No.: 10/699,153 Filing Date: October 30, 2003

Examiner: Layla G. LAUCHMAN Group Art Unit: 2877

Docket No.: TNCR.196US2 Conf. No.: 1463

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

According to 37 C.F.R. 1.98(2)(ii), copies of the U.S. Patents and U.S. Published Patent Applications documents are not required and are therefore not enclosed. Copies of the listed foreign patent documents or Other Art are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a

Attorney Docket No.: TNCR.196US2

Application No.: 10/699,153

representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee is believed to be due. The Commissioner is authorized, however, to charge any fee that may be required against Deposit Account No. 502664. This form is being submitted in duplicate.

Respectfully submitted,



James S. Hsue
Reg. No. 29,545

March 30, 2006

Date

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U.S. Department of Commerce, Patent and Trademark		Atty. Docket No.		Application No.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		TNCR.196US2		10/699,153	
		Applicant(s)		Conf. No.	
(Use several sheets if necessary)		Ibrahim ABDULHALIM et al.		1463	
APR 03 2006 (Form PTO-1449)		Filing Date		Art Group	
		October 30, 2003		2877	
U.S. Patent Documents					
*Examiner Initial	Document Number	Date	Name	Class	Subclass
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2	4,200,395	04-1980	Smith et al.		
3	4,332,473	06-1982	Ono		
4	4,703,434	10-1987	Brunner		
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26	6,710,876 B1	03-2004	Nikoonahad et al.		
Examiner		Date Considered			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.</p>					

U.S. Department of Commerce, Patent and Trademark			Atty. Docket No.			Application No.		
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(Form PTO-1449)			Filing Date			Art Group		
			October 30, 2003			2877		
U.S. Published Patent Application Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	33	2002/0018217 A1	02-2002	Weber-Grabau et al.				
	34	2002/0192577 A1	12-2002	Fay et al.				
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	35	WO 01/073824	10-2001	WIPO				
	36	WO 01/097279	12-2001	WIPO				
	37	WO 02/015238	02-2002	WIPO				
	38	WO 02/025708	03-2002	WIPO				
	39	WO 02/025723	03-2002	WIPO				
	40	WO 02/035300	05-2002	WIPO				
	41	WO 02/065545	08-2002	WIPO				
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Examiner			Date Considered					
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		October 30, 2003	2877
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
	44	Notification of Transmittal of the International Search Report or the Declaration, in corresponding PCT/US02/11026, dated 18 September 2002, 4 pages.	
	45	Written Opinion issued by the IPÉA in corresponding PCT/US02/11026, dated 11 April 2003, 4 pages.	
	46	"Light Diffraction Based Overlay Measurement", Bischoff et al., Proceedings SPIE, Vol. 4344-28 (2001), 12 pages.	
	47	Lithography Process Control, Tutorial Texts in Optical Engineering, Levinson, SPIE Press Vol. TT28, Chapter 5, "Overlay" (1999), 36 pages.	
	48	"Rigorous Coupled Wave Analysis of Planar-Grating Diffraction", Moharam et al., Vol. 71, No. 7, July 1981, J. Opt. Soc. Am., pp. 811-818.	
	49	"Exact Eigenfunctions for Square-Wave Gratings: Application to Diffraction and Surface-Plasmon Calculations", Physical Review B, Vol. 26, No. 6, 15 Sep 1982, pp. 2907-2916.	
	50	"A Modal Analysis of Lamellar Diffraction Gratings in Conical Mountings", Li, Journal of Modern Optics, 1993, Vol. 40, No. 4, pp. 553-573.	
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Examiner		Date Considered	
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.</p>			